

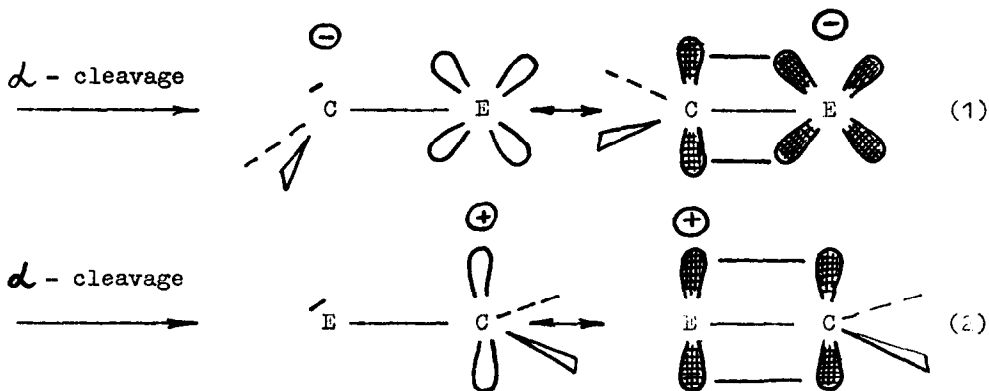
THE NEGATIVE ION MASS SPECTRA OF ORGANIC.
 COMPOUNDS OF THE GROUP IV-B ELEMENTS

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The apparently effective $p_{\sigma} - d_{\pi}$ stabilization of M-1 fragments (1) in the negative ion mass spectra of tetramethylsilane and tetramethylstannane, which, in principle, is analogous to the stabilization of positive fragments by atoms with lone pairs (2), leads to the conclusion that negative ion mass spectrometry may be a useful structural method for organic compounds containing atoms with empty orbitals.



TABLE

Com- pounds		Ionizing energy ^a (eV)	Relative Abundance (%) of Fragments (m/e) for Si ²⁸ and Sn ¹²⁰										
			Me ₃ ECH ₂ ⁻ M-1 ⁻	Me ₃ E ⁻ or Me ₂ HECH ₂ ⁻	Me ₂ ECH ⁻ or MeE(CH ₂) ₂ ⁻	MeECH ₂ ⁻	MeECH ⁻ or E(CH ₂) ₂ ⁻	MeE ⁻ or HECH ₂ ⁻	ECH ₂ ⁻	ECH ⁻	HC ₂ ⁻	CH ₃ ⁻	CH ⁻
			(87)	(73)	(71)	(57)	(56)	(43)	(42)	(41)	(25)	(15)	(13)
Me ₄ Si	4 ^b		100	-	5	-	-	-	-	-	10	3	6.6
	7.8 ^b		100	0.5	2.2	0.5	-	-	-	-	0.3	0.3	0.2
	30		100 ^c	-	20	11	2.7	3.3	12	8.7	11	1.3	11
	56		10	-	1.5	1.3	0.8	2.8	7.5	16.8	100	1.8	11.3
Me ₄ Sn	8 ^b		(179) 100	(165) 8.5	(163) -	(149) 64	(148) -	(135) 4.4	(134) -	(133) -	(25) -	(15) -	(13) -
	30		20.6 ^c	100	-	51	16	20	-	-	17.7	7.4	7

^aEnergy distribution of electrons is 0.4 eV width at half-height with ionizing current of 10 μ A.

^bResonance maxima of M-1⁻ ions.

^cComparison of these figures brings out the greater ability of Si in comparison with Sn to partake in p_J-d_J interaction.

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